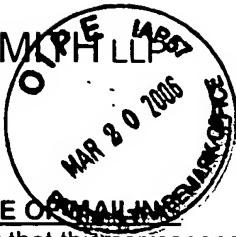


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Customer No. 026418

Date: 03/17/06

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Docket No. JG-SU-5198/500577.20056

Applicant(s): Jun FURUKAWA

Serial No.: 10/784,411

Group: 1722

Filed: February 23, 2004

Examiner: Robert M. Kunemund

For: METHOD OF IDENTIFYING DEFECT DISTRIBUTION IN SILICON SINGLE CRYSTAL INGOT

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313.1450

STATUS REQUEST

Sir,

Please advise the status of the above-identified application and when we can expect to receive an official communication.

Please direct all future telephone calls to:

Jules E. Goldberg, Esq.
(212) 521-5403
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599 Lexington Avenue (29th Floor)
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Respectfully submitted,

March 17, 2006
JEG:ram

By: *Jules E. Goldberg*
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